

Description

The FDS4435BZ uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} =-30 V I_D = -11A

 $R_{DS(ON)}$ < 16m Ω @ V_{GS}=10V

Application

Battery protection

Load switch

Uninterruptible power supply

Package Marking and Ordering Information

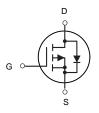
Product ID	Pack	Marking	Qty(PCS)
FDS4435BZ	SOP-8(SOIC-8)	4435 XXX YYY	3000

Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

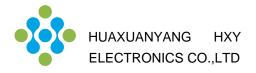
Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	- 30	V
VGS	Gate-Source Voltage	±20	V
I₀@T _A =25°C	Drain Current ³ , V _{GS} @ 10V	-11	А
IDM	Pulsed Drain Current ¹	-40	А
P₀@T₄=25℃	Total Power Dissipation	3.7	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
Rthj-a	Maximum Thermal Resistance, Junction-ambient ³	33.8	°C/W



SOP-8 (SOIC-8)



P-Channel MOSFET



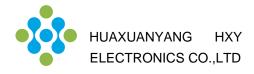
Electrical Characteristics (TJ = 25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	cteristic	ł		1		
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = -250µA	-30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -30V, V _{GS} =0V,	-	-	-1	μA
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA
On Charac	cteristics					
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D = -250µA	-1.0	-1.6	-2.5	V
	Static Drain-Source on-Resistance	V _{GS} = -10V, I _D = -10A	-	13	16	
$R_{DS(on)}$		V _{GS} = -4.5V, I _D = -5A	-	18	27	mΩ
Dynamic (Characteristics					
Ciss	Input Capacitance	V _{DS} = -15V, V _{GS} =0V, f=1.0MHz	-	1330	-	pF
Coss	Output Capacitance		_	183	-	pF
Crss	Reverse Transfer Capacitance		-	156	-	pF
Qg	Total Gate Charge		-	22	-	nC
Q _{gs}	Gate-Source Charge	V _{DS} = -15V, I _D = -5A, V _{GS} = -10V	-	1.0	-	nC
Q_gd	Gate-Drain("Miller") Charge	- VGS 10 V	-	1.8	-	nC
Switching	Characteristics					
t _{d(on)}	Turn-on Delay Time		-	9	-	ns
tr	Turn-on Rise Time	V _{DD} = -15V, I _D = -10A,	-	13	-	ns
$t_{d(off)}$	Turn-off Delay Time	V_{GS} =-10V, R _{GEN} =2.5 Ω	-	48	-	ns
t _f	Turn-off Fall Time		-	20	-	ns
Drain-Sou	rce Diode Characteristics and Maxim	um Ratings				
ls	Maximum Continuous Drain to Source Diode Forward Current		-	-	-11	А
I _{SM}	Maximum Pulsed Drain to Source Dic	num Pulsed Drain to Source Diode Forward Current		-	-40	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S = -15A	-	-0.8	-1.2	V
trr	Reverse Recovery Time	T J =25 ℃,	-	64	-	ns
Qrr	Reverse Recovery Charge	V _{DD} = -24V,I _F =-2.8A, dI/dt=-100A/µs	-	25	-	nC

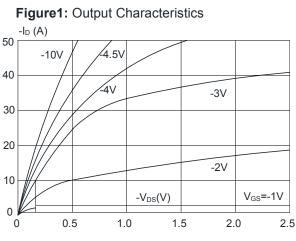
Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

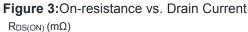
2. EAS condition: T_J=25 $^\circ \!\! \mathbb{C}$, V_Gs=10V, R_G=25\Omega, L=0.5mH, I_{AS}=-12.7A

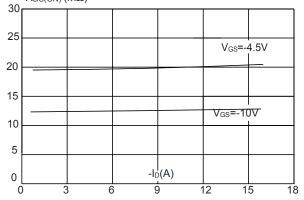
3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%

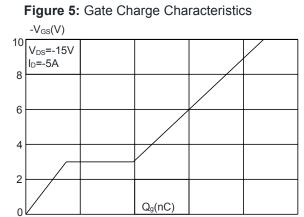


Typical Characteristics







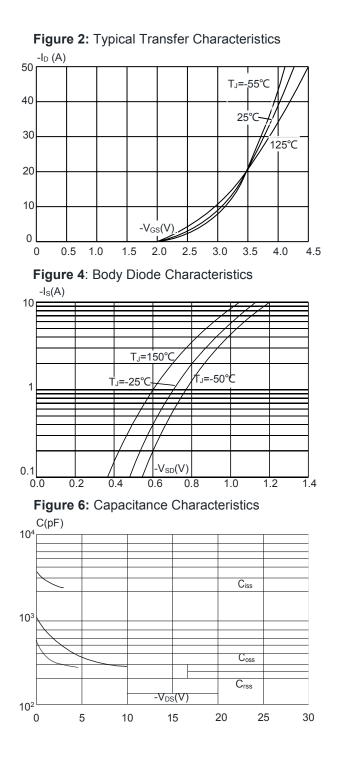


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15

20

25

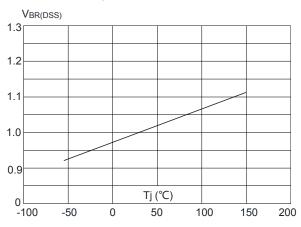


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Figure 7: Normalized Breakdown Voltage vs. Junction Temperature





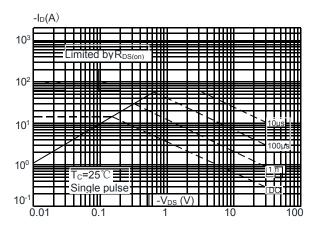


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

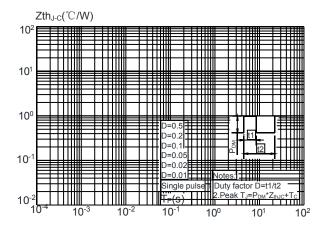


Figure 8: Normalized on Resistance vs. Junction Temperature

FDS4435BZ

P-Channel Enhancement Mode MOSFET

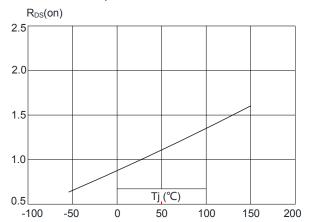
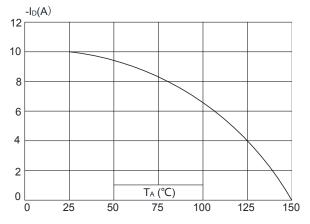
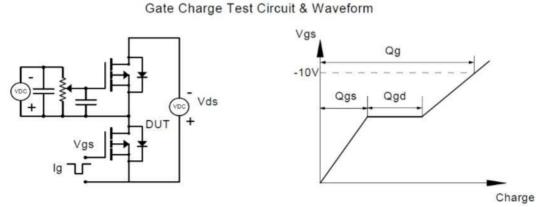


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

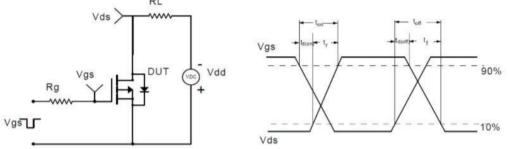




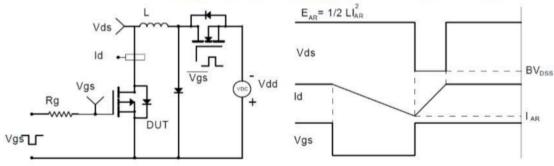
Test Circuit



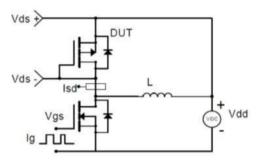
Resistive Switching Test Circuit & Waveforms

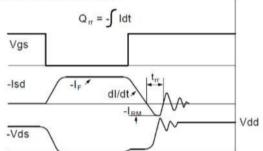


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

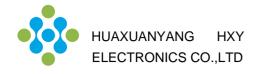


Diode Recovery Test Circuit & Waveforms

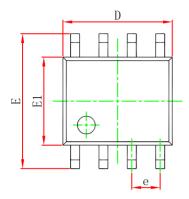


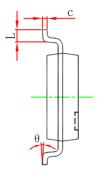


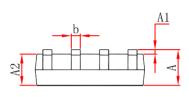
RL



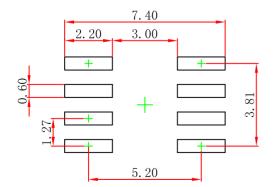
SOP-8(SOIC-8) Package Outline Dimensions







Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
А	1.350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
с	0.170	0.250	0.007	0.010	
D	4.800	5.000	0.189	0.197	
e	1.270 (BSC)		0.050 (BSC)		
E	5.800	6.200	0.228	0.244	
E1	3.800	4.000	0.150	0.157	
L	0.400	1.270	0.016	0.050	
θ	0 °	8°	0 °	8°	



- Note: 1.Controlling dimension: in millimeters.
- 2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.



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